

# INTERNATIONAL STANDARD

# NORME INTERNATIONALE

BASIC EMC PUBLICATION  
PUBLICATION FONDAMENTALE EN CEM

**Electromagnetic compatibility (EMC) –  
Part 4-1: Testing and measurement techniques – Overview of IEC 61000-4 series**

**Compatibilité électromagnétique (CEM) –  
Partie 4-1: Techniques d'essai et de mesure – Vue d'ensemble de la série  
CEI 61000-4**

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## INTERNATIONAL ELECTROTECHNICAL COMMISSION

**ELECTROMAGNETIC COMPATIBILITY (EMC) –****Part 4-1: Testing and measurement techniques –  
Overview of IEC 61000-4 series**

## FOREWORD

- 1) The International Electrotechnical Commission (IEC) is a worldwide organization for standardization comprising all national electrotechnical committees (IEC National Committees). The object of IEC is to promote international co-operation on all questions concerning standardization in the electrical and electronic fields. To this end and in addition to other activities, IEC publishes International Standards, Technical Specifications, Technical Reports, Publicly Available Specifications (PAS) and Guides (hereafter referred to as "IEC Publication(s)"). Their preparation is entrusted to technical committees; any IEC National Committee interested in the subject dealt with may participate in this preparatory work. International, governmental and non-governmental organizations liaising with the IEC also participate in this preparation. IEC collaborates closely with the International Organization for Standardization (ISO) in accordance with conditions determined by agreement between the two organizations.
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International Standard IEC 61000-4-1 has been prepared by IEC technical committee 77: Electromagnetic compatibility.

This standard forms Part 4-1 of IEC 61000. It has the status of a basic EMC publication in accordance with IEC Guide 107.

This third edition cancels and replaces the second edition, published in 2000. It constitutes a technical revision. Changes introduced in this third edition are for the purpose of updating the text to include reference to the latest publications of the IEC 61000-4 series.

The text of this standard is based on the following documents:

FDIS	Report on voting
77/319/FDIS	77/324/RVD

Full information on the voting for the approval of this standard can be found in the report on voting indicated in the above table.

This publication has been drafted in accordance with the ISO/IEC Directives, Part 2.

The committee has decided that the contents of this publication will remain unchanged until the maintenance result date indicated on the IEC web site under "<http://webstore.iec.ch>" in the data related to the specific publication. At this date, the publication will be

- reconfirmed;
- withdrawn;
- replaced by a revised edition, or
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## INTRODUCTION

The IEC 61000 series is published in several parts according to the following structure:

### **Part 1: General**

General consideration (introduction, fundamental principles)

Definitions, terminology

### **Part 2: Environment**

Description of the environment

Classification of the environment

Compatibility levels

### **Part 3: Limits**

Emission limits

Immunity test levels (in so far as they do not fall under the responsibility of the product committees)

### **Part 4: Testing and measurement techniques**

Measurement techniques

Testing techniques

### **Part 5: Installation and mitigation guidelines**

Installation guidelines

Mitigation methods and devices

### **Part 6: Generic standards**

### **Part 9: Miscellaneous**

Each part is further subdivided into several parts, published either as International Standards, technical specifications or technical reports, some of which have already been published as sections. Others will be published with the part number followed by a dash and completed by a second number identifying the subdivision (example: 61000-6-1).

## **ELECTROMAGNETIC COMPATIBILITY (EMC) –**

### **Part 4-1: Testing and measurement techniques – Overview of IEC 61000-4 series**

#### **1 Scope and object**

This part of IEC 61000 covers testing and measuring techniques for electric and electronic equipment (apparatus and systems) in its electromagnetic environment.

The object of this part is to give applicability assistance to the technical committees of IEC or other bodies, users and manufacturers of electrical and electronic equipment on EMC standards within the IEC 61000-4 series on testing and measurement techniques and to provide general recommendations concerning the choice of relevant tests.

#### **2 Normative references**

The following referenced documents are indispensable for the application of this document. For dated references, only the edition cited applies. For undated references, the latest edition of the referenced document (including any amendments) applies.

IEC 60050(161), *International Electrotechnical Vocabulary (IEV) – Chapter 161: Electromagnetic compatibility*

IEC 61000-1-1, *Electromagnetic Compatibility (EMC) – Part 1-1: General – Application and interpretation of fundamental definitions and terms*

IEC 61000-2-5, *Electromagnetic Compatibility (EMC) – Part 2: Environment – Classification of electromagnetic environments*

IEC 61000-3-2, *Electromagnetic compatibility (EMC) – Part 3-2: Limits – Limits for harmonic current emissions (equipment input current  $\leq 16$  A per phase)*

IEC 61000-3-3, *Electromagnetic compatibility (EMC) – Part 3-3: Limits – Limitation of voltage changes, voltage fluctuations and flicker in public low-voltage supply systems, for equipment with rated current  $\leq 16$  A per phase and not subject to conditional connection*

IEC/TS 61000-3-4, *Electromagnetic compatibility (EMC) – Part 3-4: Limits – Limitation of emission of harmonic currents in low-voltage power supply systems for equipment with rated current greater than 16 A*

IEC/TR 61000-3-5, *Electromagnetic compatibility (EMC) – Part 3-5: Limits – Limitation of voltage fluctuations and flicker in low-voltage power supply systems for equipment with rated current greater than 16 A*

IEC 61000-3-6, *Electromagnetic compatibility (EMC) – Part 3: Limits – Section 6: Assessment of emission limits for distorting loads in MV and HV power systems*



IEC 61000-3-11, *Electromagnetic compatibility (EMC) – Part 3-11: Limits – Limitation of voltage changes, voltage fluctuations and flicker in public low-voltage supply systems – Equipment with rated current  $\leq 75$  A and subject to conditional connection*

IEC 61000-3-12, *Electromagnetic compatibility (EMC) – Part 3-12: Limits – Limits for harmonic currents produced by equipment connected to public low-voltage systems with input current  $> 16$  A and  $\leq 75$  A per phase*

IEC 61000-4-2, *Electromagnetic compatibility (EMC) – Part 4-2: Testing and measurement techniques – Electrostatic discharge immunity test*

IEC 61000-4-3, *Electromagnetic compatibility (EMC) – Part 4-3: Testing and measurement techniques – Radiated, radio-frequency, electromagnetic field immunity test*

IEC 61000-4-4, *Electromagnetic compatibility (EMC) – Part 4-4: Testing and measurement techniques – Electrical fast transient/burst immunity test*

IEC 61000-4-5, *Electromagnetic compatibility (EMC) – Part 4-5: Testing and measurement techniques – Surge immunity test*

IEC 61000-4-6, *Electromagnetic compatibility (EMC) – Part 4-6: Testing and measurement techniques – Immunity to conducted disturbances, induced by radio-frequency fields*

IEC 61000-4-7, *Electromagnetic compatibility (EMC) – Part 4-7: Testing and measurement techniques – General guide on harmonics and interharmonics measurements and instrumentation, for power supply systems and equipment connected thereto*

IEC 61000-4-8, *Electromagnetic compatibility (EMC) – Part 4-8: Testing and measurement techniques – Power frequency magnetic field immunity test*

IEC 61000-4-9, *Electromagnetic compatibility (EMC) – Part 4-9: Testing and measurement techniques – Pulse magnetic field immunity test*

IEC 61000-4-10, *Electromagnetic compatibility (EMC) – Part 4-10: Testing and measurement techniques – Damped oscillatory magnetic field immunity test*

IEC 61000-4-11, *Electromagnetic compatibility (EMC) – Part 4-11: Testing and measurement techniques – Voltage dips, short interruptions and voltage variations immunity test*

IEC 61000-4-12, *Electromagnetic compatibility (EMC) – Part 4-12: Testing and measurement techniques – Oscillatory waves immunity test*

IEC 61000-4-13, *Electromagnetic compatibility (EMC) – Part 4-13: Testing and measurement techniques – Harmonics and interharmonics including mains signalling at a.c. power port, low frequency immunity tests*

IEC 61000-4-14, *Electromagnetic compatibility (EMC) – Part 4-14: Testing and measurement techniques – Voltage fluctuation immunity test*

IEC 61000-4-15, *Electromagnetic compatibility (EMC) – Part 4-15: Testing and measurement techniques – Flickermeter – Functional and design specifications*<sup>1</sup>

IEC 61000-4-16, *Electromagnetic compatibility (EMC) – Part 4-16: Testing and measurement techniques – Test for immunity to conducted common mode disturbances in the frequency range 0 Hz to 150 kHz immunity test*

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<sup>1</sup> Revision of IEC 60868.

IEC 61000-4-17, *Electromagnetic compatibility (EMC) – Part 4-17: Testing and measurement techniques – Ripple on d.c. input power port immunity test*

IEC 61000-4-18, *Electromagnetic Compatibility (EMC) – Part 4-18: Testing and measurement techniques – Oscillatory wave immunity test*

IEC 61000-4-20, *Electromagnetic compatibility (EMC) – Part 4-20: Testing and measurement techniques – Emission and immunity testing in transverse electromagnetic (TEM) waveguides*

IEC 61000-4-21, *Electromagnetic compatibility (EMC) – Part 4-21: Testing and measurement techniques – Reverberation chamber test methods*

IEC 61000-4-23, *Electromagnetic compatibility (EMC) – Part 4-23: Testing and measurement techniques – Test methods for protective devices for HEMP and other radiated disturbances*

IEC 61000-4-24, *Electromagnetic compatibility (EMC) – Part 4: Testing and measurement techniques – Section 24: Test methods for protective devices for HEMP conducted disturbance*

IEC 61000-4-25, *Electromagnetic compatibility (EMC) – Part 4-25: Testing and measurement techniques – HEMP immunity test methods for equipment and systems*

IEC 61000-4-27, *Electromagnetic compatibility (EMC) – Part 4-27: Testing and measurement techniques – Unbalance, immunity test*

IEC 61000-4-28, *Electromagnetic compatibility (EMC) – Part 4-28: Testing and measurement techniques – Variation of power frequency, immunity test*

IEC 61000-4-29, *Electromagnetic compatibility (EMC) – Part 4-29: Testing and measurement techniques – Voltage dips, short interruptions and voltage variations on d.c. input power port immunity tests*

IEC 61000-4-30, *Electromagnetic compatibility (EMC) – Part 4-30: Testing and measurement techniques – Power quality measurement methods*

IEC 61000-4-32, *Electromagnetic compatibility (EMC) – Part 4-32: Testing and measurement techniques – High-altitude electromagnetic pulse (HEMP) simulator compendium*

IEC 61000-4-33, *Electromagnetic compatibility (EMC) – Part 4-33: Testing and measurement techniques – Measurement methods for high power transient parameters*

IEC 61000-4-34, *Electromagnetic compatibility (EMC) – Part 4-34: Testing and measurement techniques – Voltage dips, short interruptions and voltage variations immunity tests for equipment with input current more than 16 A per phase*

### **3 Terms and definitions**

For the purposes of this document, the definitions in IEC 60050(161) apply.

## 4 General

In the past, electromechanical devices and systems were generally not sensitive to electromagnetic disturbances (i.e. conducted and radiated electromagnetic disturbances and electrostatic discharge). The electronic components and equipment now in use are much more sensitive to these disturbances, particularly to "high-frequency" and "transient" phenomena. The tremendous expansion in the use of electronic components and equipment has increased the danger and importance of malfunctioning, damage, etc. which can arise from electric and electromagnetic disturbances.

The product committees (or users and manufacturers of equipment) remain responsible for the appropriate choice of the immunity tests from the IEC 61000-4 series and the test level to be applied to their equipment. However, to enhance the task of coordination and standardization, the product committees or users and manufacturers should consider the recommendations given in this standard.

## 5 Structure of the IEC 61000-4 series standards

The structure of standards within the IEC 61000-4 series in general follows the guidance given in IEC Guide 107. For the basic testing standards of the series, that structure is as follows:

1. Scope
2. Normative references
3. Terms and definitions
4. General
5. Test levels/limits
6. Test equipment
7. Test set-up
8. Test procedures
9. Evaluation of test results
10. Test report

There are standards within the IEC 61000-4 series, which are not basic testing standards (for example IEC 61000-4-7). They are standards related to measurement (instrumentation and procedures), which do not necessarily follow the above-mentioned structure.

## 6 Selection of tests

Tests can be applied to equipment for many reasons, for example

- design tests during development;
- type tests;
- acceptance tests;
- production tests.

Equipment should be subjected to all tests necessary to provide the required reliability, but, for economic reasons, the number of tests may be limited to a reasonable minimum. It is acceptable that the number of tests for acceptance or production testing is reduced in comparison with type tests.